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**AEHR TEST SYSTEMS ANNOUNCES FIRST PRODUCTION ORDERS FOR  
NEXT-GENERATION FOX™ SEMICONDUCTOR TEST SYSTEMS**

**Fremont, CA (May 30, 2013) - Aehr Test Systems (Nasdaq: AEHR)**, a worldwide supplier of semiconductor test and burn-in equipment, announced today that it has received an order totaling nearly \$2 million, with a 30% down payment, for multiple production systems of its next-generation FOX Semiconductor Test System from a leading manufacturer of flash memory devices. The systems are expected to ship in the first half of calendar 2014.

"This order for FOX-1Ps is the first order of what we believe will lead to multiple follow-on systems as our customer ramps capacity in several of their facilities worldwide," said Gayn Erickson president and chief executive officer at Aehr Test Systems. "They are a great lead customer for this new product, and we have already garnered additional interest from several other customers looking at our new FOX-1P for production functional test, wafer level burn-in and process monitor applications.

"There is a lot of interest in our highly-parallel FOX test solutions from IC manufacturers around the world, especially those who are implementing built-in self-test (BIST) and design-for-testability (DFT) features into their products," continued Erickson. "We believe that our FOX family of single and multiple wafer test systems represents a significant breakthrough in meeting the continuous cost of test reductions needed as customers achieve full wafer test. With our unique architecture which allows thousands of individual device power supplies (DPS), 10x or more than other ATE systems, as well as all input/output (I/O), with per pin resources, we are able to address the specific test challenges required by low pin count DFT and BIST modes of the latest logic and memory devices such as microcontrollers, smart cards and flash memory devices."

The next generation FOX-1P extends the capabilities of the Aehr Test FOX-1 by adding high density, low cost I/O and DPS modules with the capability to provide over 16,000 I/O or DPS channels in a single test head for massive parallelism on a single wafer. It has resources to test over 10,000 die on a single wafer with individual DPS channels. Each channel has current monitoring and provides protection of the device and the probe cards that connect the test system to the devices under test.

Aehr Test's FOX family of products is focused on full wafer high reliability test and sort test needs for products such as automotive ICs, memories and devices with embedded memories, including microcontrollers and smart cards.

### **About Aehr Test Systems**

Headquartered in Fremont, California, Aehr Test Systems is a worldwide provider of test systems for burning-in and testing logic and memory integrated circuits and has an installed base of more than 2,500 systems worldwide. Increased quality and reliability needs of the Automotive and Mobility integrated circuit markets are driving additional test requirements, capacity needs and opportunities for Aehr Test products in package and wafer level test. Aehr Test has developed and introduced several innovative products, including the ABTS™ and FOX families of test and burn-in systems and the DiePak® carrier. The ABTS system is used in production and qualification testing of packaged parts for both low-power and high-power logic as well as all common types of memory devices. The FOX system is a full wafer contact test and burn-in system used for burn-in and functional test of complex devices, such as leading-edge memories, digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit Aehr Test's website at [www.aehr.com](http://www.aehr.com).

### **Safe Harbor Statement**

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test's products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the FOX technologies, acceptance by customers of the FOX systems shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K, 10-Q and other reports from time to time filed with the Securities and Exchange Commission for a more detailed description of the risks facing our business. Aehr Test disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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